



X-RAY PHOTOELECTRON SPECTROSCOPY (XPS)

MANUFACTURER : Physical Electronics

MODEL : PHI 5600-ci spectrometer

Analysis

- Analysis of surface composition
- Depth sampled: 2 to 10 nm
- Elements observed : from Lithium

Characteristics

- Surface descum possible
- Variable angle analysis
- Analyzed area: from $300 \mu\text{m}^2$ to 0.8mm^2